

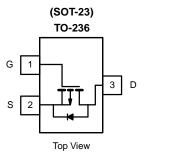
RoHS COMPLIANT HALOGEN

FREE

SI2303BDS-T1-GE3-VB Datasheet

P-Channel 30 V (D-S) MOSFET

PRODUC	CT SUMMARY		
V _{DS} (V)	R _{DS(on)} (Ω) Typ.	I _D (A) ^a	Q _g (Typ.)
	0.046 at V _{GS} = - 10 V	- 5.6	
- 30	0.049 at V _{GS} = - 6 V	- 5	11.4 nC
	0.054 at V _{GS} = - 4.5 V	-4.5	





FEATURES

- Trench Power MOSFET
- 100 % R_g Tested



- For Mobile Computing
 - Load Switch
 - Notebook Adaptor Switch
 - DC/DC Converter

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 30	V	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C		- 5.6		
	T _C = 70 °C		- 5.1		
	T _A = 25 °C	I _D	- 5.4 ^{b,c}		
	T _A = 70 °C		- 4.3 ^{b,c}	А	
Pulsed Drain Current (t = 100 µs)	•	I _{DM}	- 18		
Continuus Courses Durin Diada Current	T _C = 25 °C		- 2.1		
Continous Source-Drain Diode Current	T _A = 25 °C	- I _S	- 1 ^{b,c}		
	T _C = 25 °C		2.5		
Mauinum Daura Diagingtian	T _C = 70 °C		1.6	14/	
Maximum Power Dissipation	T _A = 25 °C	P _D	1.25 ^{b,c}	W	
	T _A = 70 °C	1 1	0.8 ^{b,c}		
Operating Junction and Storage Temperature	e Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS

	Symbol	Typical	Maximum	Unit
$t \le 5 s$	R _{thJA}	75	100	°C/W
Steady State	R _{thJF}	40	50	0/11
		$t \le 5 \text{ s}$ R_{thJA}	t \leq 5 s R _{thJA} 75	t \leq 5 s R _{thJA} 75 100

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-				I	1
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = -250 \mu A$	- 30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 250.04		- 19		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	l _D = - 250 μA		4		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	- 0.5		- 2.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V			- 1	1.
Zero Gate Voltage Drain Current		V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, \text{ V}_{GS} = -10 \text{ V}$	- 2.5			Α
		V _{GS} =- 10 V, I _D = - 4.4 A		0.046		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} =- 6 V, I _D = - 4 A		0.049		Ω
		V _{GS} =- 4.5 V, I _D = - 3.6 A		0.054		-
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 3.4 A		18		S
Dynamic ^b				<u> </u>		ļ
Input Capacitance	C _{iss}			1295		
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		150		pF
Reverse Transfer Capacitance	C _{rss}			130		
		V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 5.4 A		24	36	nC
Total Gate Charge	Qg			11.4	17	
Gate-Source Charge	Q _{gs}	V _{DS} = - 15 V, V _{GS} = - 4.5 V, I _D = - 5.4 A		3.4		
Gate-Drain Charge	Q _{gd}			3.8		-
Gate Resistance	R _g	f = 1 MHz	1.5	7.7	15.4	Ω
Turn-On Delay Time	t _{d(on)}			13	20	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, \text{ R}_{1} = 3.5 \Omega$		4	8	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -4.3 \text{ A}, \text{ V}_{\text{GEN}} = -10 \text{ V}, \text{ R}_{\text{a}} = 1 \Omega$		38	57	
Fall Time	t _f			6	12	-
Turn-On Delay Time	t _{d(on)}			28	42	ns
Rise Time	t _r	$V_{DD} = -15 \text{ V}, \text{ R}_{L} = 3.5 \Omega$		16	24	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -4.3 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_q = 1 \Omega$		30	45	
Fall Time	t _f	B SEN SEN SEN		10	20	
Drain-Source Body Diode Characteristic				10	20	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C		[- 2.1	
Pulse Diode Forward Current ($t = 100 \mu$ s)	I _{SM}				- 80	A
Body Diode Voltage	V _{SD}	I _S = - 4.3 A, V _{GS} = 0 V		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}			15	23	ns
Body Diode Reverse Recovery Charge	Q _{rr}	4		7	14	nC
Reverse Recovery Fall Time	t _a	I _F = - 4.3 A, dl/dt = 100 A/μs, T _J = 25 °C		8	14	10
Neverse Necovery Fall Time	۰a	J		0		ns

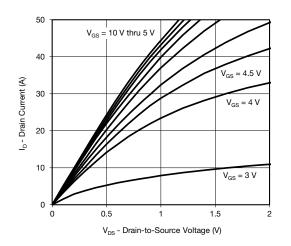
Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

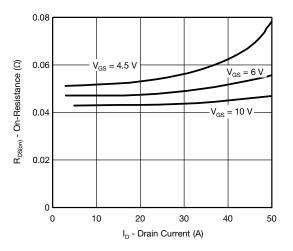
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

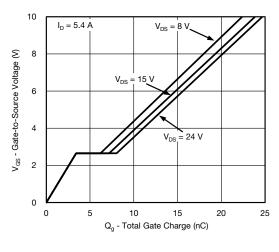




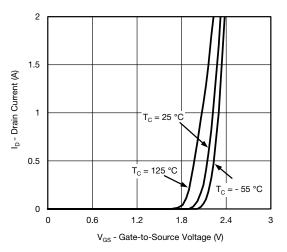
Output Characteristics



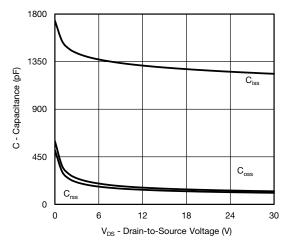
On-Resistance vs. Drain Current



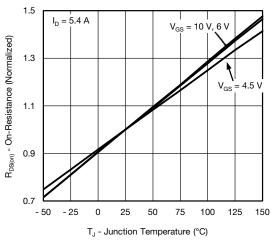
Gate Charge



Transfer Characteristics

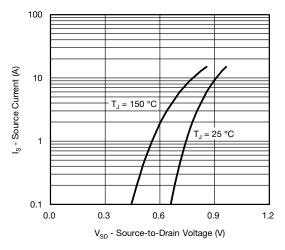


Capacitance



On-Resistance vs. Junction Temperature

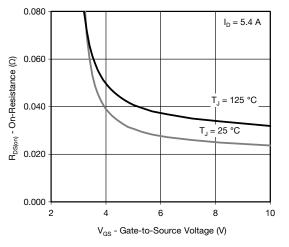




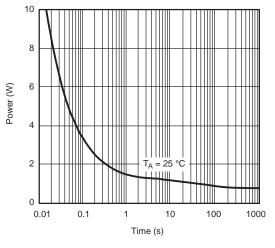
Source-Drain Diode Forward Voltage



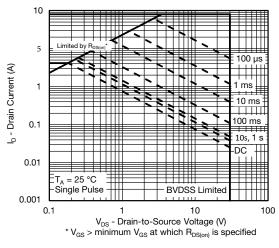




On-Resistance vs. Gate-to-Source Voltage

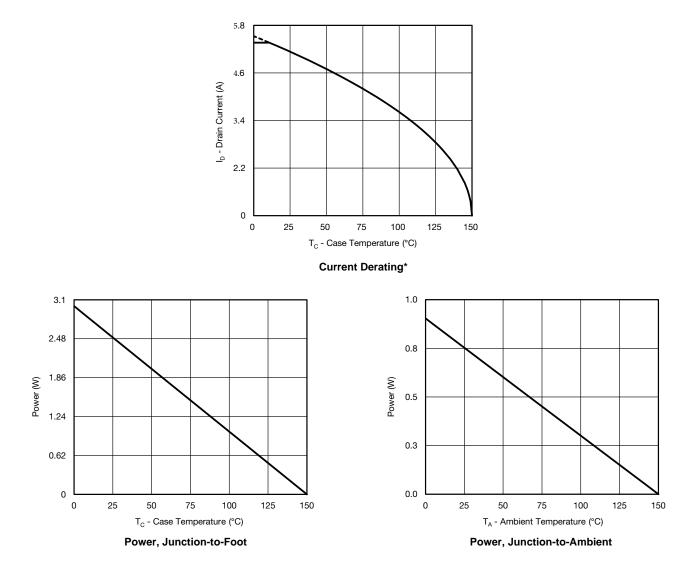


Single Pulse Power (Junction-to-Ambient)



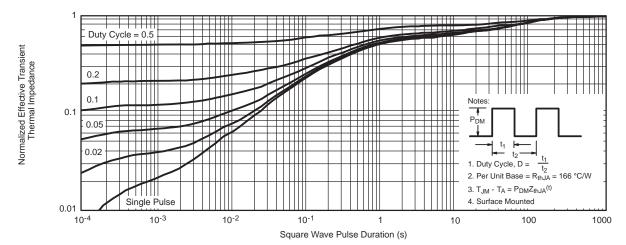
Safe Operating Area, Junction-to-Ambient





* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

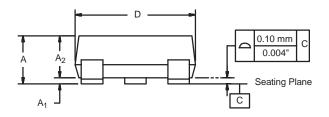


Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-23 (TO-236): 3-LEAD







Max 1.12 0.10 1.02 0.50 0.18 3.04 2.64 1.40	Min 0.035 0.0004 0.0346 0.014 0.003 0.110 0.083	Max 0.044 0.004 0.040 0.020 0.007 0.120 0.104		
0.10 1.02 0.50 0.18 3.04 2.64	0.0004 0.0346 0.014 0.003 0.110 0.083	0.004 0.040 0.020 0.007 0.120		
1.02 0.50 0.18 3.04 2.64	0.0346 0.014 0.003 0.110 0.083	0.040 0.020 0.007 0.120		
0.50 0.18 3.04 2.64	0.014 0.003 0.110 0.083	0.020 0.007 0.120		
0.18 3.04 2.64	0.003 0.110 0.083	0.007 0.120		
3.04 2.64	0.110 0.083	0.120		
2.64	0.083			
		0.104		
1.40	0.047			
	0.047	0.055		
0.95 BSC	0.037	4 Ref		
1.90 BSC		0.0748 Ref		
0.60	0.016	0.024		
0.64 Ref	0.025	5 Ref		
0.50 Ref) Ref		
8°	3°	8°		
_	0.64 Ref 0.50 Ref	0.64 Ref 0.025 0.50 Ref 0.026		

SI2303BDS-T1-GE3-VB



RECOMMENDED MINIMUM PADS FOR SOT-23



Recommended Minimum Pads Dimensions in Inches/(mm)



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